



FORM PTO 449 DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. CiphBio-11 CON	SERIAL NO. 10/758,326
	APPLICANT Sidney E. Buttrill, Jr.	
	FILING DATE January 14, 2004	GROUP 2878 2881

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
APR 18	6,674,069	01/2004	Martin et al.			
	6,600,155	07/2003	Andrien et al.			
	6,300,625	10/2001	Ishihara			
	5,696,375	12/1997	Park et al.			
	5,665,967	09/1997	Coxon et al.			
	5,365,064	11/1994	Rettinghaus			
	5,357,107	10/1994	Ibach et al.			
	5,198,666	03/1993	Bateman			
	5,194,732	03/1993	Bateman			
	5,128,543	07/1992	Reed et al.			
	5,097,125	03/1992	Gruen et al.			
	5,032,723	07/1991	Kono			
	4,973,842	11/1990	Gruen et al.			
	4,959,544	09/1990	Sukenobu			
	4,945,236	07/1990	Mogami et al.			
	4,889,987	12/1989	Gruen et al.			
	4,864,130	09/1989	Gruen et al.			
	4,855,596	08/1989	Gruen et al.			
	4,800,273	01/1989	Phillips			
	4,774,408	09/1988	Gohlke			
	4,754,135	06/1988	Jackson			
	4,472,631	09/1984	Enke et al.			
	4,234,791	11/1980	Enke et al.			
	3,986,025	10/1976	Fujiwara et al.			
	3,863,068	01/1975	Poschenrieder			
	3,745,343	07/1973	Halliday et al.			
	3,576,992	05/1971	Moorman et al.			

EXAMINER

Sidney E. Buttrill, Jr.

DATE CONSIDERED

October 15, 2004

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.	SERIAL NO.
		CiphBio-11 CON	10/758,326
		APPLICANT	
		Sidney E. Buttrill, Jr.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		FILING DATE	GROUP
		January 14, 2004	2878 2881

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
11/15	2003-086129	03/2003	Japan			Abstract	
	2000-243346	09/2000	Japan			Abstract	
	2000-243345	09/2000	Japan			Abstract	
	11-297267	10/1999	Japan			Abstract	
	11-195398	07/1999	Japan			Abstract	
	11-135061	05/1999	Japan			Abstract	
	08-007831	01/1996	Japan			Abstract	
	63-266751	11/1988	Japan			Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIALS	
11/15	Matsuda, H., "High-resolution mass spectrometer," Shitsuryo Bunseki Vol. 33, No. 4, pp 227-234 (1985).
	Matsuo, T., et al., "Ion optics of new TOF mass spectrometer in the order approximation," Nucl. Instrum. Methods Phys. Res. Sect. A, Vol. A256, No. 3, pp 327-330 (1987).
	Nose, N., "High-resolution time-of-flight analyzer for charge exchange process," Shitsuryo Bunseki Vol. 31, No. 3, pp 165-172 (1983).
	Sakurai et al., "Ion Optics for Time-of-Flight Mass Spectrometers with Multiple Symmetry," Int. J. Mass. Spectrom. Ion Proc. 63: pp 273-287 (1985).
	Sakurai et al., "A New Time-of-Flight Mass Spectrometer," Int. J. Mass. Spectrom. Ion Proc. 66: pp 283-290 (1985).
	Wollnik, Hermann, Optics of Charged Particles, Orlando: Academic Press, 1987, pp 201-205.
11/15	Wollnik, Hermann, Focusing of Charged Particles, Vol. 2, Albert Septier, ED, New York: Academic Press, 1967, pp 163-202 (Chapter 4.1).

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